A design methodology was developed that can be used to efficiently implement large-scale Photonic Page Buffer (PPB) ICs with application specific performance and functionality requirements. The PPB chip has numerous potential applications including photonic switching, non-volatile data storage (buffering), interfacing smart pixel systems with electronic hosts, implementing cache memory for optical memory devices, template matching, spatial format conversion, clock rate conversion, optical wavelength conversions, bandwidth smoothing, clock synchronization, and independent flow control for input and output channels.
Final Report

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1.1. Executive Summary

The parent AFOSR grant was focused on developing smart optoelectronic interconnection networks that combine communication and processing capabilities in network hardware to accelerate distributed computing applications. Under that program we have developed network designs that can be efficiently implemented using optical interconnects. The smart network architecture is compatible with asynchronous transfer mode (ATM) specifications. ATM is a switching technique based on the emerging integrated digital network standard (ISDN), and it can be used in telecommunication networks and in both wide and local area computer networks.

The objective of this AASERT award was to support a PhD thesis to develop optoelectronic integrated circuits to interface with the smart network (e.g. a line unit circuit). The function of a line unit is to provide an external interface, perform protocol-related functions, and implement ATM cell buffering and contention management functions. The approach we have taken is to develop a design methodology for building large-scale photonic page buffer integrated circuits. These circuits can serve as an efficient interface to an optoelectronic interconnection network. We have also uncovered numerous other applications for photonic page buffer circuits. With the methodology we have developed, one can now design line circuit with application specific functionality, performance and cost.

1.2. Personnel Supported

Dr. Fouad Kiamilev - Asst. Professor of Electrical Engineering at UNCC. Dr. Kiamilev is the principal investigator on this project. Per AASERT guidelines, no funds from this grant were used to support Dr. Kiamilev.

Gordon Aplin - Ph.D. student in the department of Electrical Engineering at UNCC. Mr. Aplin is a United States citizen.

Richard Rozier - Ph.D. student in the department of Electrical Engineering at UNCC. Mr. Aplin is a United States citizen.
Dr. Ashok Krishnamoorthy - Member of Technical Staff, AT&T Bell Laboratories. We are collaborating with Dr. Krishnamoorthy on both theoretical and hardware portions of this program. Dr. Krishnamoorthy is not funded by this program.

1.3. Publications


1.4. New Discoveries, Inventions, or Patent Disclosures


2. Photonic Page Buffer Integrated Circuits

The result of our AASERT program is a design methodology that can be used to efficiently implement large-scale Photonic Page Buffer (PPB) ICs with application specific performance and functionality requirements. The PPB chip has numerous potential applications including photonic switching, non-volatile data storage (buffering), interfacing smart pixel systems with electronic hosts, implementing cache memory for optical memory devices, template matching,
spatial format conversion, clock rate conversion, optical wavelength conversion, bandwidth smoothing, clock synchronization, and independent flow control for input and output channels. Although we developed this methodology based on the hybrid CMOS-SEED platform, we anticipate that it is compatible with other emerging smart pixel technologies that use silicon CMOS circuits. To verify the validity of our approach, a sixteen kilobit, 1008 optical I/O channel, 32 page, 504bits/page, 50Mpage/sec photonic page buffer IC with random page access capability was designed, fabricated and electrically tested. This 21mm² IC was fabricated in 0.8 micron HP26G CMOS technology [1] and integrates 200,000 transistors. Our design is based on the hybrid CMOS-SEED technology that integrates GaAs MQW photodetectors and modulators with high-volume commodity CMOS VLSI processes [2]. It uses optical device pitch and spacing of an existing GaAs MQW diode mask [3]. The CMOS optical receiver amplifier and transmitter driver circuits use proven circuits as well. The hybrid CMOS-SEED technology was selected based on its availability, maturity and experience.

Since our design takes advantage of existing electronic memory circuits, it is highly scalable. With present 0.4 micron CMOS, a 16 megabit PPB chips can be built using SRAM circuits. With future 0.18 micron CMOS technology, the capacity can be increased to 256 megabits [4]. Using DRAM circuits, an additional 4X increase in memory size can be achieved with some reduction in memory access time. The number of optical I/O channels is dependent on the optoelectronic device technology and the on-chip power consumption of receiver/transmitter circuits. With present CMOS-SEED technology, 200-1000 optical I/O channels can be achieved with power consumption of 3-5 mW per channel operating at 50-100 Mbps/channel. This corresponds to a total throughput of 10-100 gigabits per second. In comparison, Rambus, which is a high-performance electronic memory, achieves a throughput 2 gigabits per second [5]. The work carried out by this AASERT builds on our earlier effort that produced a two kilobit 21,000 transistor photonic page buffer IC [6]. The 64 optical I/O channels on this IC were tested at 50Mb/s/channel optical data throughput; corresponding to an aggregate optical data I/O bandwidth of 3.2Gb/s in a 1mm² chip area.

3. Applications of Photonic Page Buffer ICs

A block diagram for a PPB with M address lines, $2^M$ words, N bits per memory word is shown in figure 1. The inputs to the PPB include an N-bit data-input bus (DIN), an M-bit address bus (A), write enable (WR) control signal, and other optional application-specific control signals (see section 4). An N-bit data-output bus (DOUT) forms the output of the PPB. The write data enters PPB optically through the DIN port and is optically read out at the DOUT port. The A bus is the input port to address the $2^M$ words in the memory. Many applications exist for PPB chips with random page access capability. Although distinct applications may require a slightly different PPB design, the design methodology presented here can efficiently realize such application-specific requirements. The paragraphs that follow describe several PPB applications. Due to the complexity of each application, no detailed description will be attempted here.
Electronic interface for Photonic systems: Typically, smart pixel systems are electrically connected to an electronic host computer. The PPB provides an efficient mechanism to accomplish this task. In this application, data enters the PPB optically through the N-bit DIN port. There, it is buffered and converted into a K-bit data stream that is electrically brought outside the chip. In the reverse direction, an electrical K-bit data stream enters the chip. There, it is buffered and assembled into an N-bit vector that is optically written to the DOUT port. For example, a PPB design may have 1000 optical channels running at 100Mbps/channel and 64 electrical channels running at 50Mbps/channel.

Scratchpad memory for Smart Pixel Systems: Smart pixel designs often require high-speed memory and the PPB can efficiently serve this purpose. For example, one smart pixel design [7] uses eleven PPB chips as part of a twenty-chip high-performance FFT processor. This processor can compute a new 1,024-point complex FFT in every 0.44 μsec. In retrospective, a high-performance electronic system that uses 4 Sharp LH9124 FFT processor chips, 12 Sharp LH9320 address generator chips, 12 SRAM chips, and various glue-logic chips requires 31 μsec for the same computation [8].

Cache memory for 3-D Optical Memory Devices: The use of smart-pixel ICs as cache memory for 3-D optical memory devices was recently proposed [9]. In this application, a smart pixel IC provides an efficient interface to a low-latency, wide-word optical memory. The PPB design methodology presented here, can be applied to build smart pixel ICs described in reference 9.

Photonic Switching: As shown in figure 2, the PPB can implement a memory-based time-division switch [10]. In this scheme, different channels are put on an N-bit optical TDM (time division multiplexing) bus, with successive slots containing information on different channels. The PPB acts as a central queue for incoming packets. An off-chip controller circuits serially routes the incoming packets. For example, a single PPB chip with 1000 optical channels running at 100Mbps/channel can implement a 16 port switch running at 6.25Gbps/port. The aggregate throughput of this single-chip switch design will be 100 Gigabits/sec.

Photonic FIFO: First-in first-out (FIFO) memories help interface switching and computing systems by providing non-volatile storage (buffering), clock synchronization, asynchronous-to-
synchronous conversion, bandwidth smoothing, improved jitter/skew tolerance, and independent flow control for input and output channels. By adding a small control circuit, the PPB can be made to emulate a photonic FIFO memory [11].

Optical Data Format Conversion: The PPB can be used to convert between different optical formats. For example, a PPB chip with 1000 optical input channels can read 1000-bit optical planes at 1KHz clock rate, convert this data to bit-serial format, and write it to a single optical output channel at 1Ghz clock rate.

Template Matching: In this application, the PPB memory is first loaded with templates. Then, optical bit-plane data entering the PPB is compared against these templates to find the best match. Finally, the results are reported to the host controller. This application can be performed at high-speed by adding logic circuitry to the basic PPB design as described in section 4.

![Figure 2: Single-chip TDM switch using photonic page buffer IC. For 4 ports at 622Mbps, the aggregate bandwidth of PPB device must support 2.5Gbps.](image)

4. Smart Pixel IC Layout

Smart pixel IC integrate a rectangular array of optical transmitter and receiver devices on top of an electronic integrated circuit. This integration can be monolithic or hybrid. For example, the hybrid CMOS-SEED platform uses flip-chip bonding. The placement of optical devices directly on top of integrated circuits is necessary to minimize the interconnect capacitance, and hence power consumption, for interconnects between the IC and the optoelectronic device array. Using a rectangular array of optoelectronic devices with a fixed pitch simplifies system design, and, in the case of flip-chip bonding, leads to higher flip-chip yield as compared with random placement approaches. It should be noted, random placement of optical transmitter and receiver devices can be effectively accomplished by not using all of the devices in the rectangular array. The paragraphs that follow review chip layout methods used in smart pixels and introduce the chip layout methodology selected for our photonic page buffer design.
One emerging method for efficiently combining high-performance electronic circuit layouts with optoelectronic devices is to integrate optical devices directly over active silicon VLSI circuits (see figure 3). For example, a two kilobit 21,000 transistor photonic page buffer IC organized as a 32 words deep and 32 bits per word First-In First-Out (FIFO) memory was recently demonstrated [6]. The 64 optical I/O channels on this IC were individually tested at 50Mb/s/channel data throughput; corresponding to an aggregate optical data I/O bandwidth of 3.2Gb/s in a 1mm² chip area. Although this approach works well for moderately sized designs, it has several limitations when applied to large chips. First, the length of the electrical wire connecting optical devices to the transimpedance amplifier (for optical receiver device) or to the driver (for optical transmitter device) increases with the size of the chip. This leads to higher interconnect capacitance, higher power consumption and increased latency. For example, the capacitance of a typical hybrid CMOS-SEED modulator is under 100fF while a 0.5 mm electrical wire has a capacitance in excess of 1000fF. The second limitation is specific to our photonic page buffer design. As will be discussed shortly, our design uses SRAM circuits to achieve high storage density. Internally, SRAMs use weak analog signals that are amplified by sense amplifiers located at the periphery of the device. To ensure signal integrity on these lines, routing of high-speed digital signals directly over SRAMs is typically not permitted. Thus it becomes difficult to integrate optical devices directly over large SRAM circuits and at the same time achieve high-speed operation.
Figure 4. Example of “smart pixel” layout style where a single circuit is replicated in a two-dimensional array. The layout shown, implements 4x4 array of smart pixels.

Another popular smart pixel layout methodology is to design a self-contained “smart pixel” circuit with electronic processing circuitry, optical transmitter/receiver circuitry, and optical I/O devices. This circuit is then replicated in a two-dimensional “smart pixel” array structure as shown in figure 4. While this approach is highly effective and popular, its drawback for building large-scale photonic page buffers is low storage density. In this approach, register files are typically used for memory function. An edge-triggered register uses 24 transistors to store a single bit, as compared with six transistors in the SRAM circuit [12]. Addition of random page access capability would require additional control circuitry, further increasing the transistor count per memory bit. On the other hand, the use of high-density SRAM circuits with this approach is difficult because existing RAM layouts are not easily partitionable onto a “smart pixel” array structure.

Figure 5: The proposed layout approach integrates receiver amplifier circuits, transmitter driver circuits, and optical devices within a photonic interface module (PIM), placed in the center of the chip. Existing VLSI layouts can then be placed around the PIM.
Our scheme is a compromise between these two approaches. It places the array of optical devices directly over their corresponding receiver amplifier and transmitter driver circuits. The resulting two-dimensional array structure, called the photonic interface module, is located in the center of the integrated circuit. The memory circuits are then placed around the photonic interface module as shown in figure 5. With this approach, the electronic and the photonic portions of the IC design can be optimized separately. For example, the memory structure can use existing high-density SRAM circuit layouts. On the other hand, the photonic interface array can be designed to locate the driver/receiver circuitry near the optical devices with which they communicate to achieve optimum performance. While we have described this layout scheme in the context of photonic page buffer ICs, it can be applied to other large-scale smart pixel IC designs [7]. Finally, it should be pointed out, that this layout scheme is specifically targeted for large-scale smart pixel ICs that permit optical device arrays with tight pitch, such as the hybrid CMOS-SEED platform.

5. Architecture of Photonic Page-Buffer IC

5.1. Memory Architecture Selection

A number of efficient circuit designs exist for memory structures including dynamic RAM (DRAM), static RAM (SRAM), First-In First-Out (FIFO), stack, Read-Only Memory (ROM), and register file. For our photonic page buffer design, we have selected the SRAM circuit based on its high-speed, low-power consumption, and high storage density characteristics. Efficient circuit designs for SRAMs are readily available [12] and they can be fabricated by commercial silicon foundries. With small additional controller circuitry, SRAMs can efficiently emulate FIFO and stack functionality [11]. The paragraphs that follow describe the considerations that led to the selection of the SRAM over other memory structures for our PPB design.

A DRAM uses a single transistor circuit for storing one memory bit; thus, it achieves the highest storage density as compared with other memory circuits [12]. On the other hand, efficient implementation of DRAM circuitry requires special processing steps that are typically not available from commercial silicon foundries. Also, DRAMs are typically slower than SRAMs due to the increased sensitivity requirements placed on its sense amplifiers. For these reasons we have chosen not to use the DRAM circuit in our photonic page buffer design.

Both the FIFO and stack circuits are high-speed circuit designs that are well suited for small-scale designs [12]. Scaling these circuits to large capacity is difficult due to (1) high power-consumption, since all transistors in the circuit can change state during a memory access and (2) low storage density, due to large number of transistors required for storing one memory bit. For these reasons, we have chosen not to use these circuits for our photonic page buffer design.

Finally, although register file is the fastest memory circuit, it was not selected for the photonic page buffer design because of low density and high power consumption. On the other hand, the ROM was not chosen because of its limited application since ROM contents cannot be changed after the chip is fabricated.
5.2. **Architecture of High-Speed Static RAM**

A block diagram for asynchronous static RAM circuit with M address lines, $2^M$ words, N bits per memory word was shown in figure 1. The inputs to the RAM include an N-bit data-input bus (DIN), an M-bit address bus (A), write enable (WR) control signal, and the optional output enable (OE) control signal. An N-bit data-output bus (DOUT) forms the output of the RAM. The write data enters RAM through the DIN port and is read out at the DOUT port. The A bus is the input port to address the $2^M$ words in the memory.

Writing to the RAM is performed in three steps. First the address bus (A) is set to the memory address that is being written to. At the same time, the data-input (DIN) bus is set to the data to be written. Second, the write signal (WR), which normally stays high, is pulled low and held there for a specified time period ($t_{wp}$). Third, when the WR signal goes high, the data on the DIN bus is written to memory. As typical for edge-triggered storage circuits, the DIN bus must remain unchanged for a specified amount of time before (i.e. setup time) and after (i.e. hold time) the rising edge of the WR signal.

Reading from the RAM is accomplished in two steps. First, the address bus (A) is set to the memory address that is being read from. Second, after a specified amount of time ($t_{ac}$), the contents of that memory location appear on the data-output (DOUT) bus.

![Figure 6: General organization for the static RAM circuit.](image)

Since the RAM does not allow simultaneous read and write access, the DIN and DOUT buses can use the same physical wiring, leading to reduced on-chip wiring density. In this case, the DOUT bus must use tri-state drivers that are set to high-impedance state when the RAM is being
written to. Additional input control signal, called output enable (OE), is added to the RAM design to control these tri-state drivers.

Because of the size and complexity of RAM circuitry, no detailed discussion will be attempted here [12]. Instead, we will describe the general layout of the RAM; how the components of the RAM are implemented for variable word size, memory size, bits-per-column and tri-state output; and how these components are brought together into a physical layout. Our discussion emphasizes the aspects of the RAM layout that are relevant for photonic page buffer IC implementation.

Figure 6 shows the general layout of a high speed static RAM. The heart of the RAM is a memory array. To the left of the array is the row decode circuitry, the address buffers, and the control signal buffers. Below the array is the column decode, read/write circuitry, and input/output circuitry. The paragraphs that follow describe these components of the RAM.

![Memory array organization](image)

**Figure 7:** Memory array organization. This example shows a memory with 32 four-bit words and a bpc of 4.

The memory array is a grid of memory cells, each storing 1 bit using a 6 transistor circuit. As figure 7 shows, the memory cell consists of two cross-coupled inverters and two pass transistors. The memory cells are placed in a two-dimensional array reflecting user specified word size, number of words and bits per column. Word size (bhw) determines the number of multi-bit columns. Number of words (words) and bits-per-column (bpc) determines the number of rows. For a given RAM capacity and word size, the bits-per-column parameter allows the designer to control the aspect ratio (ratio of height to width) of the RAM layout. This parameter is used in our methodology to adjust the RAM aspect ratio to match the size of the photonic interface array. Figure 8 shows a memory array containing 32 four-bit words with a bpc of four. The array is filled from left to right, and from bottom to top. Thus the first word occupies bit 0 of each column of row 0, the second word occupies bit 1 of each column of row 0, and so on, with every fifth word moving up to the next row. Addressing a word consists of selecting the row and the bit column occupied by the word. This is simplified by requiring that the bpc always be a multiple of 2. This way, the \( N \) lower bits of the address, where \( N = \log_2(bpc) \), will always
correspond exactly to the column bit number and the remaining bits of the address will always correspond exactly to the row number.

Several control signal in the RAM, such as the output enable (OE) signal, have large fanout. To ensure high-speed operation, these signals are driven using a cascaded chain of optimally sized inverters [12]. This takes place in the control buffer. On the other hand, the internal column data-output lines (DL and DLB in figure 11) carry weak analog signals that are amplified to digital levels using sense amplifier circuits. To maintain signal integrity on these lines, routing of high-speed digital signals directly over the RAM circuit is typically not permitted. Our design methodology for photonic page buffer ICs does not violate this routing constraint. This completes the discussion of the static RAM circuit.

5.3. Architecture of Photonic Interface Module
As discussed previously, the photonic interface module integrates optical devices directly over the corresponding transmitter-driver/receiver-amplifier circuitry (see figure 5). Its purpose is to convert between off-chip optical bit-plane data and on-chip digital electrical signal formats. The resulting electrical signals are routed to the periphery of the photonic interface module for connection with memory circuits. The interconnect density and power consumption associated with this wire routing are important issues when large number of optical I/O channels are used. For example, consider a 2mm x 2mm photonic interface module for hybrid CMOS-SEED technology. In 0.8 micron HP26G CMOS process, with 2.6 micron interconnect pitch, 3,077 signals can be brought to the periphery of the module. In practice, the actual number of I/O signals that can be supported by this interface module will be lower since the transmitter-driver and the receiver-amplifier circuits with properly sized power rails occupy 2500 μm² of die area (see section 5). This reduces the number of I/O signals to 1,600 (4mm²/2500 μm²). Using a conservative estimate, that average routing wire length is 4 mm, the power consumption per routing wire at 100MHz clock rate becomes:

\[
P_{Diss} = \frac{1}{2} \cdot C \cdot V^2 \cdot F = \frac{1}{2} \cdot \left( \frac{2PF}{cm} \cdot 0.4\,cm \right) \cdot (5v)^2 \cdot 100\,MHz = 1mWatt
\]

Increase in the number of I/O signals can be achieved using larger photonic interface modules or smaller feature size CMOS technology. For example, in 0.5 micron HP14TB CMOS process [13], with 1.4 micron interconnect pitch, a 4mm x 4mm photonic interface module can support in excess of 10,000 optical I/O signals. In addition, the power consumption will be reduced since HP14TB operates with a 3v power supply.

5.4. Architecture of Photonic page buffer IC
The chip floorplan for a generic photonic page buffer IC was shown in figure 5. The photonic interface module, located at the center of the chip, provides 2N optical channels, organized as N inputs and N outputs. An N-bit wide and 2^M-bit deep RAM is divided into four N/4-bit RAM banks that surround the photonic interface module. The RAM bpc design parameter is adjusted to achieve high packing density. Between the RAM bank and the photonic interface module there is an optional set of N/4 vectored cells, called a datapath, that contain application-specific
logic circuitry. Typically, the datapath is "folded" into multiple columns to match the height of the RAM bank. The datapath concept allows one to add application-specific functionality to the photonic page buffer design, including boundary scan testing, electrical read/write RAM interface, parity generation and checking, CRC error checking and correction, and data coding.

The M-bit address bus, the RAM write enable control signal, the optional RAM output enable control signal, and the datapath control signals are routed to the periphery of the chip for electrical connection. The write data enters the photonic page buffer optically through an N-bit DIN port and is optically read out at the N-bit DOUT port. In this design, the control signals and the M address bits are controlled electrically. A number of variations are possible for the basic design discussed here. For example, RAM addressing and control can be performed optically. Alternatively, with VCSEL-based technologies it may be appropriate to use fewer optical channels operating at higher speed. In this case, the number of electrical channels on the chip will exceed the number of optical I/O channels, and additional multiplexing circuits will be required to convert between these two formats.

5.5. Scalability and performance analysis

Since our design takes advantage of existing electronic RAM circuits, its storage capacity is highly scalable. For example, 16-Mbit static RAM devices with access times of 10 to 15 nanoseconds have been demonstrated in 0.4 micron CMOS technology [14,15,16]. With future 0.18 micron CMOS technology, the total capacity can be increased to 256 megabits [4]. Although electronic static RAM ICs use a small number of external I/O channels, internally, the RAM is a highly parallel device capable of supporting large word sizes as discussed in section 4.2. This characteristic makes these devices suitable for large-scale photonic page buffers with high-density and large word size. Using DRAM circuits instead of SRAMs, an additional 4X increase in memory size can be achieved with some reduction in memory access time. For example, 64-Mbit dynamic RAM devices with access times of 30 to 50 nanoseconds have been demonstrated in 0.4 micron CMOS technology [17,18]. With 0.25 micron CMOS technology, 256-Mbit dynamic RAM devices become possible [19]. With future 0.18 micron CMOS technology, the total DRAM capacity is projected at 1,000 megabits [4]. The drawback of DRAM circuits is their requirement for specialized CMOS processing which may be incompatible with logic and analog amplifier circuits used in our PPB design methodology. Finally, the power consumption for CMOS RAM circuits is extremely.

The number of optical I/O channels in the PPB is dependent on the optoelectronic device technology and the on-chip power consumption of receiver/transmitter circuits. For example, with current CMOS-SEED technology, 200-1000 optical I/O channels can be achieved with power consumption of 3-5 mW per optical channel operating at 50-100 Mbps/channel [6,7]. This corresponds to a total throughput of 10-100 gigabits per second and on-chip power consumption of 1 to 5 Watts. In comparison, Rambus, which is a high-performance electronic memory, achieves a throughput 2 gigabits per second [5]. Ultimately, optical pin-count may be limited by other considerations such as optical channel bit-error rate and overall system design considerations.
6. **A 16-Kb Photonic Page-Buffer IC**

To verify the validity of our methodology, a sixteen kilobit, 1008 optical I/O channel, 32 page, 504bts/page, 50Mpage/sec PPB IC with random page access capability was designed, fabricated and electrically tested. This 21mm² IC was fabricated in 0.8 micron HP26G CMOS technology and integrates 200,000 transistors. Our design is based on the hybrid CMOS-SEED technology. It uses optical device pitch and spacing of an existing GaAs MQW diode mask [3]. The CMOS single-beam optical receiver amplifier and single-beam transmitter driver circuits use proven circuits as well. In particular, our receiver uses a design with a demonstrated maximum bit-rate of 375Mb/s with a power consumption of 3.5 mW and minimum switching energy of 60fJ [20].

![Photomicrograph of the 16-Kb photonic page buffer IC fabricated in HP26G CMOS for hybrid CMOS-SEED.](image)

Figure 8 shows the layout of the 16-Kb PPB chip. The photonic interface module (PIM) is 2mm x 1mm in size and supports 1,008 optical I/O channels. The 504 input channels are arranged in a 18 x 28 diode array located in the upper 1 mm x 1 mm portion of the PIM that uses 35 micron vertical and 65 micron horizontal pitch. The 504 output channels use a similar layout and are placed in the lower 1mm x 1mm portion of the PIM. Optical receiver and transmitter circuit are placed directly under the MQW diode that they service. Because of tight MQW diode pitch, only 2275 µm² is available for these circuits. The 1,008 electrical signals are routed to the east and west sides of the PIM. The use of two PIM sides, rather than four, for routing electrical signals was selected to reduce chip fabrication costs and to simplify power distribution for the PIM. The PPB chip uses two memory banks, organized as 32-bit deep 252-bit wide RAMs with a bpc value of 1, that are placed around the PIM. A datapath module, having 252 vectored logic cells, is placed between each memory bank and the PIM. The datapath module is folded into three
columns, each column having 84 logic cells, to match the height of the memory bank. Because the
PIM receiver circuits use a transimpedance amplifier design with static power dissipation of
3.5mW, the power rail routing and sizing for a PIM with 504 receivers has to be carefully
considered. Our design uses wide power rails (100X minimum metal width) and multiple
redundant power pins to ensure that the PIM is adequately powered.

Figure 9: Functional diagram for the 16Kbit PPB design. A 504-bit tri-state bus connects all the
components on the chip. This figure shows two adjacent bus lines and associated circuitry.
Dashed lines show connections between circuitry on adjacent bus lines. Control signals (S0, S1,
CLK, CLR, OE_RAM, OE_RX, OE_REG) are electrically brought outside the chip.

Figure 9 shows the functional diagram for the 16Kbit PPB design. A 504-bit tri-state bus connects all the components on the chip. These components include the RAM, the datapath, the optical output array, and the optical input array. The control signals and the 5 address bits are controlled electrically. As discussed earlier, the logic circuits in the datapath can add application-specific functionality to the basis PPB design. In our case, each datapath cell contains tri-state drivers for driving the bus, a 2-to-1 multiplexer circuit, and an edge-triggered flip-flop with parallel load and serial shift capability. The shift-in and shift-out lines of flip-flops in adjacent datapath cells are connected forming a 504-bit shift-register. The shift-in and shift-out lines for this register are electrically brought outside of the chip. This datapath scheme permits electrical boundary scan test capability and permits serial electrical access to the PIM and the RAM modules. The paragraphs that follow describe the various modes of operation possible with the 16-Kb PPB design.

Electrical read/write memory access: Here the PPB chip is used as a 16-Kb RAM with a bit-serial
electrical interface. Writing data requires multiple clock cycles. First, 504 clock cycles are used
to serially load the 504-bit register. Next the contents of the register are written in parallel to the
desired RAM address as discussed in section 4.2. Reading data uses a similar approach.
Optical read/write access: Here the PPB chip is used as a photonic RAM with random access to 32 504-bit pages. The write data enters the photonic page buffer optically through an 504-bit DIN port and is optically read out at the 504-bit DOUT port.

Electro-optical read/write access: This mode combines the two operations described above to translate between electrical and optical data formats.

Optical test mode: This mode was developed to allow simple parallel testing of the optical device array. Here, the optical input channels are directly connected to their corresponding output channels. Thus an incoming 504-bit optical plane of 1's produces an output 504-bit optical plane of 1's, permitting one to quickly locate defective optical devices.

Spatial Format Converter: Here the 16-Kb PPB is optically loaded with 504-bit optical data planes. The shift-register is used to multiplex this data onto K optical output channels, where K<504. Alternatively, the reverse of this operation is also possible. For example, the 16-Kb can to input a bit-serial optical stream at 300Mbps, convert it into parallel format, and output a 504-bit optical data plane at 0.6Mbps.

Electrical testing of the 16-Kb PPB chip was performed using a custom printed circuit board with a XILINX FPGA acting as the RAM controller and using a 64-channel 50MHz digital logic analyzer. Figure 10 shows the a 100Mbps electrical bit pattern being written into the PPB chip. Electrical testing has demonstrated proper function of the electrical circuits at 100MHz clock rates. Static chip power consumption was measured at 2.5 Watts as expected. Although optical testing of the 16-Kbit PPB was not performed, we anticipate that the optical devices and associated driver circuits will be able to operate at 50MHz since they use proven designs that have shown 300Mb/s optical operation in previous designs.

![Figure 20: High-speed test results showing page readout at 100MHz clock rate. Waveform (b) shows the output of the shift register containing the MSB of SRAM word being read, while waveform (b) shows the incoming 100MHz clock signal.](image-url)


